

GaN - Gallium Nitride

Electrical properties

Basic Parameters

[Basic Parameters for Zinc Blende crystal structure](#)

[Basic Parameters for Wurtzite crystal structure](#)

Basic Parameters for Zinc Blende (cubic) crystal structure

Breakdown field	$\sim 5 \times 10^6$ V cm ⁻¹	300 K
Mobility electrons	$= < 1000$ cm ² V ⁻¹ s ⁻¹	300 K
Mobility holes	$= < 350$ cm ² V ⁻¹ s ⁻¹	300 K
Diffusion coefficient electrons	25 cm ² s ⁻¹	300 K
Diffusion coefficient holes	9 cm ² s ⁻¹	300 K
Diffusion coefficient holes	3.2×10^5 m s ⁻¹	300 K
Diffusion coefficient holes	9.5×10^4 m s ⁻¹	300 K

Basic Parameters for Wurtzite crystal structure

Breakdown field	$\sim 5 \times 10^6$ V cm ⁻¹	300 K
Mobility electrons	$= < 1000$ cm ² V ⁻¹ s ⁻¹	300 K
Mobility holes	$= < 200$ cm ² V ⁻¹ s ⁻¹	300 K
Diffusion coefficient electrons	25 cm ² s ⁻¹	300 K
Diffusion coefficient holes	5 cm ² s ⁻¹	300 K
Diffusion coefficient holes	2.6×10^5 m s ⁻¹	300 K
Diffusion coefficient holes	9.4×10^4 m s ⁻¹	300 K

[Chow & Ghezzo \(1996\)](#)

Breakdown field 3.3×10^6 V cm⁻¹ 300 K

[Chow & Ghezzo \(1996\)](#)

Conductivity $\sigma = 6 \div 12 \Omega^{-1}$ cm⁻¹ 300 K ; $n \approx 10^{17}$ cm⁻³, undoped layers grown by vaporphase technique on sapphire

[Ilegems \(1972\); Ilegems & Dingle \(1973\); Crouch et al. \(1978\)](#)

Mobility electrons $\mu_n = < 440$ cm² V⁻¹ s⁻¹ 300 K ; purest material, $n \approx 10^{17}$ cm⁻³

[Ilegems \(1972\); Ilegems & Dingle \(1973\); Crouch et al. \(1978\)](#)

